

EddyCus® map 2530RM – Resistivity Imaging Device

P_2530RM_24



Highlights

- ▶ Contact-free imaging
- ▶ High speed (10,000 points in 5 min)
- ▶ Repeatable and accurate
- ▶ High resolution (9 to 90,000 points)
- ▶ Mapping of encapsulated layers
- ▶ Homogeneity and defect imaging

Processes

- ▶ Classification and sorting
- ▶ Ingot casting and drawing (FZ, CZ)
- ▶ Implantation and doping
- ▶ Annealing and tempering
- ▶ Composition & structure assessment
- ▶ Melting, sintering, heat treatment
- ▶ EDM processability

SURAGUS GmbH
Maria-Reiche-Strasse 1
01109 Dresden
Germany

For further questions:
+49 351 32 111 520

sales@suragus.com

Applications

- ▶ Wafer resistivity imaging
- ▶ Ingot and boule resistivity imaging
- ▶ Sputter target composition imaging
- ▶ Purity assessment
- ▶ Electrical discharge machining
- ▶ Material sorting (map: homogeneity assessment)
- ▶ Melting, casting, sintering
- ▶ Defect imaging and integrity assessment

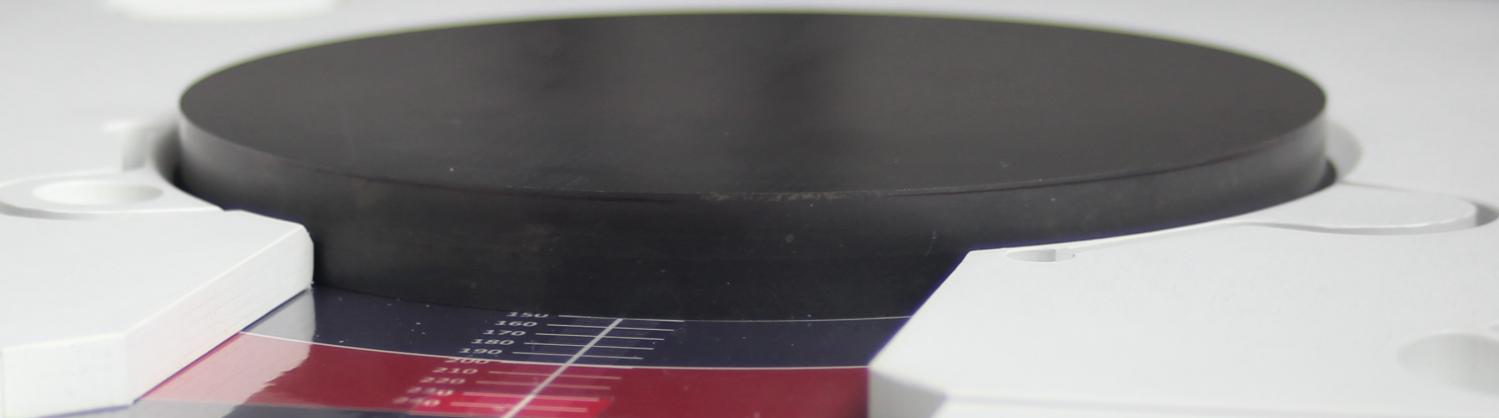
Materials

- ▶ Semiconductors
 - ▶ Si (mono, poly)
 - ▶ SiC, SiSiC
 - ▶ GaAs
 - ▶ GaN
- ▶ Alloys
- ▶ Metals
- ▶ Graphite
- ▶ Graphene
- ▶ Compounds
- ▶ Composites

Visit us at:
www.suragus.com
www.suragus.com/calculator
www.suragus.com/EddyCusMap2530

Engineered and Made in Germany 





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|------------------------------------|---|
| Measurement technology | High frequency eddy current sensor |
| Substrates | Flat, slightly curved |
| Max. scanning area | 12 inch / 300 mm x 300 mm x 10 mm |
| Edge effect correction / exclusion | 2 – 10 mm (depending on size, range, setup and requirements) |
| Max. sample thickness / sensor gap | 10 mm |
| Resistivity range | 0.002 – 0.1 mOhm·cm 0.1 – 100 mOhm·cm 100 – 1,000 mOhm·cm |
| Conductivity range | 0.01 – 65 MS/m |
| Min. pitch | 0.1 mm |
| Mode | Contact and non-contact |
| Speed | 400 mm per second (time 1 to 30 minutes) |
| Device dimensions (w/h/d) / weight | 31.5" x 19.1" x 33.5" / 785 mm x 486 mm x 850 mm / 90 kg |
| Further available features | Sheet resistance imaging, metal thickness imaging, anisotropy and sheet resistance sensor |

Device Control and Software

- ▶ Pre-defined measurement and product recipes (sizes, pitches, thresholds)
- ▶ Line scan, histogram and area analysis
- ▶ Black and colored image coding
- ▶ Csv & pdf export
- ▶ SPC summary and export
- ▶ 3 user levels
- ▶ Material database for parameter conversion
- ▶ Edge effect compensation
- ▶ Storage and import of data
- ▶ Export of data sets (e.g. to EddyEva, MS Excel, Origin)

